



Attorney Docket No.: CYPR-CD00179

**IN THE UNITED STATES PATENT AND TRADEMARK OFFICE**

Patent Application

Inventor(s): Warren Snyder      Group Art Unit:

Filed: 10/05/01      Examiner:

Serial No.: 09/972,319

Title: METHOD FOR APPLYING INSTRUCTIONS TO MICROPROCESSOR IN TEST MODE

Form 1449

**U.S. Patent Documents**

Examiner Initial	No.	Patent No.	Date	Patentee	Class	Sub-class	Filing Date
MM	A	6,144,327	11/07/00	Distinti et al.	341	126	08/12/97
MM	B	5,202,687	04/13/93	Distinti	341	158	06/12/91
	C						
	D						
	E						
	F						

**Foreign Patent or Published Foreign Patent Application**

Examiner Initial	No.	Document No.	Publication Date	Country or Patent Office	Class	Sub-class	Translation
	G						
	H						
	I						

**Related Pending US Patent Applications**

Examiner Initial	No.	Docket Number, Title, Filing Date, Serial Number & Inventors
MM	J	CYPR-CD00176; "TEST ARCHITECTURE FOR MICROCONTROLLER PROVIDING FOR A SERIAL COMMUNICATION INTERFACE"; 10/05/01; 09/972,003; W. Snyder
MM	K	CYPR-CD00178; "METHOD FOR ENTERING CIRCUIT TEST MODE"; 10/05/01; 09/972,133; W. Snyder
Examiner	<i>Michael Markulin</i>	Date Considered 9/11/04

Examiner: Initial citation considered. Draw line through citation if not in conformance and not considered.  
Include copy of this form with next communication to applicant.

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